


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/620,532	FARNHAM ET AL.	
	Examiner	Art Unit	
	Sean E. Aeder, Ph.D.	1642	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
530		350			424	185.1				
INTERNATIONAL CLASSIFICATION										
C	0	7	K	1/00						
A	6	1	K	39/00						
				/						
				/						
				/						
Sean E Aeder (Assistant Examiner) (Date)					JEFFREY SIEW JEFFREY SIEW SUPERVISORY PATENT EXAMINER Jeffrey Siew (Primary Examiner) 6/19/08					Total Claims Allowed: 4 O.G. Print Claim(s) first
Kim Downing (Legal Instruments Examiner) (Date)										O.G. Print Fig. none

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original		
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